Form PTO 1449 (Modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATT OOCKET NO. 211810US99 SERIAL NO.

09/911,495

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Barbara F. BARENBURG, et al. GROUP

FILING DATE

				July 25, 2001		GROOF	2838
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XAMINER		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
INITIAL_	AA	3,802,967	04/09/74	Ladany et al.		02,00	三 豆
	AB	4,174,422	11/13/79	Matthews et al.		1 1	- F
-+	AC	4,404,265	09/13/83	Manasevit			82
	AD	4,482,906	11/13/84	Hovel et al.			111 R 2800
	AE	4,523,211	06/11/85	Morimoto et al.		1	
	AF	4,661,176	04/28/87	Manasevit			
	AG	4,793,872	12/27/88	Meunier et al.	"		
	АН	4,846,926	07/11/89	Kay et al.			
	AJ	4,855,249	08/08/89	Akasaki et al.			
	ΑI	4,891,091	01/02/90	Shastry			
	AK	4,912,087	03/27/90	Aslam et al.			
	AL	4,928,154	05/22/90	Umeno et al.			
	АМ	4,963,949	10/16/90	Wanlass et al.			
	AN	5,141,894	08/25/92	Bisaro et al.			
	AO	5,159,413	10/27/92	Calviello et al.			
	AP	5,173,474	12/22/92	Connell et al.			
	AQ	5,221,367	06/22/93	Chisholm et al.			
	AR	5,225,031	07/06/93	McKee et al.			
	AS	5,358,925	10/25/94	Neville Connell et al.			
	ΑT	5,393,352	02/28/95	Summerfelt			·-
	ΑU	5,418,216	05/23/95	Fork			
	AV	5,450,812	09/19/95	McKee et al.			
	AW	5,478,653	12/26/95	Guenzer			
	AX	5,482,003	01/09/96	McKee et al.			
	AY	5,514,484	05/07/96	Nashimoto			
	AZ	5,556,463	09/17/96	Guenzer			
	ВА	5,588,995	12/31/96	Sheldon			
1	ВВ	5,670,798	09/23/97	Schetzina			
	ВС	5,733,641	03/31/98	Fork et al.			-
	BD	5,735,949	04/07/98	Mantl et al.			
	BE	5,741,724	04/21/98	Ramdani et al.			
	BF	5,810,923	09/22/98	Yano et al.			
	BG	5,830,270	11/03/98	McKee et al.			
	вн	5,912,068	06/15/99	Jia		ļ	
	ВІ	6,020,222	02/01/00	Wollesen			
	BJ	6,045,626	04/04/00	Yano et al.		<u> </u>	
	вк	6,064,078	05/16/00	Northrup et al.		<u> </u>	
	BL	6,064,092	05/16/00	Park			140
	вм	6,096,584	08/01/00	Ellis-Monaghan et al.			_
	BN	6,103,008	08/15/00	McKee et al.			
	ВО	6,136,666	10/24/00	So			
	BP	6,174,755	01/16/01	Manning		ļ	
60	BQ	6,180,486	01/30/01	Leobandung et al.			

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EXAMINER	Ī	DOCUMENT	DATE	NAME	CLASS	SUB	FILING IF APPRO	ATE
INITIAL	CA	NUMBER 3,766,370	10/16/73	Walther		CLASS	IF APPROM	KIATE
<u> </u>	СВ	4,006,989	02/08/77	Andringa		 		200
	СС	4,284,329	08/18/81	Smith et al.	-	 		
	CD	4,777,613	10/11/98	Shahan et al.				
	CE	4,802,182	01/31/89	Thornton et al.			_	-
	CF	4,882,300	11/21/89	Inoue et al.		1		
-	CG	4,896,194	01/23/90	Suzuki				
-	СН	4,999,842	03/12/91	Huang et al.				
	CI	5,081,062	01/14/92	Vasudev et al.				
	CJ	5,155,658	10/13/92	Inam et al.				
_	СК	5,248,564	09/28/93	Ramesh				
	CL	5,260,394	11/09/93	Tazaki et al.		-		
	СМ	5,270,298	12/14/93	Ramesh				
	CN	5,286,985	02/15/94	Taddiken				
	co	5,310,707	05/10/94	Oíshi et al.			_	
	CP	5,326,721	07/05/94	Summerfelt				-
	ca	5,404,581	04/04/95	Honjo		1		
_	CR	5,418,389	05/23/95	Watanabe		 	<u>.</u>	
	cs	5,436,759	07/25/95	Dijaii et al.				
	СТ	5,576,879	11/19/96	Nashimoto				
-	cu	5,606,184	02/25/97	Abrokwah, et al.				
	cv	5,640,267	06/17/97	May et al.				
	cw	5,674,366	10/07/97	Hayashi et al.				
	сх	5,729,641	03/17/98	Chandonnet et al.				
	CY	5,790,583	08/04/98	Но				
	cz	5,825,799	10/20/98	Ho et al.	-	1		
	DA	5,857,049	01/05/99	Beranek et al.			 .	
	DB	5,874,860	02/23/99	Brunel et al.				
	DC	5,926,496	07/20/99	Ho et al.			,	
	DD	5,937,285	08/10/99	Abrokwah, et al.		† †		
	DE	5,981,400	11/09/99	Lo				
	DF	5,990,495	11/23/99	Ohba			-	_
	DG	6,002,375	12/14/99	Corman et al.				
	DH	6,008,762	12/28/99	Nghiem				
	DI	6,055,179	04/25/00	Koganei et al.				
	DJ	6,107,653	08/22/00	Fitzgerald				
	DK	6,113,690	09/05/00	Yu et al.				
	DL	6,114,996	09/05/00	Nghiem				
	DΜ	6,121,642	09/19/00	Newns				
1	DN	6,128,178	10/03/00	Newns				
	DO	6,143,072	11/07/00	McKee et al.				
	DP	6,184,144	02/06/01	Lo				
500	DQ	6,222,654	04/24/01	Frigo				

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Cas	EA	4,484,332	11/20/84	Hawrylo		02.100	2800
1	EB	4,815,084	03/21/89	Scifres et al.			8
	EC	4,876,219	10/24/89	Eshita et al.			
	ED	4,963,508	10/16/90	Umeno et al.			
	EE	5,060,031	10/22/91	Abrokwah, et al.			
	EF	5,063,166	11/05/91	Mooney et al.			
	EG	5,116,461	05/26/92	Lebby et al.			1
	EH	5,127,067	06/30/92	Delcoco et al.			
	ΕI	5,144,409	09/01/92	Ma			
	EJ	5,293,050	03/08/94	Chapple-Sokol et al			
	EK	5,356,831	10/18/94	Calviello et al.			
	EL	5,391,515	02/21/95	Kao et al.			
	EM	5,442,191	08/15/95	Ма			
	EN	5,444,016	08/22/95	Abrokwah, et al.			
	EO	5,480,829	01/02/96	Abrokwah, et al.			
	EP	5,528,414	06/18/96	Oakley			
	EQ	5,614,739	03/25/97	Abrokwah et al.		<u> </u>	
- 	ER	5,729,394	03/17/98	Sevier et al.		1	
	ES	5,731,220	03/24/98	Tsu et al.		1	
	ET	5,764,676	06/09/98	Paoli et al.		<u> </u>	
	EU	5,777,762	07/07/98	Yamamoto			
	EV	5,778,018	07/07/98	Yoshikawa et al.			
	EW	5,778,116	07/07/98	Tomich			
	EX	5,801,105	09/01/98	Yano et al.			
	EY	5,828,080	10/27/98	Yano et al.			
	EZ	5,858,814	01/12/99	Goossen et al.		<u> </u>	
+	FA	5,861,966	01/19/99	Ortel			
	FB	5,883,996	03/16/99	Knapp et al.	-	1	
	FC	5,995,359	11/30/99	Klee et al.			
	FD	6,058,131	05/02/00	Pan			
	FE	6,137,603	10/24/00	Henmi		 	
-	FF	6,146,906	11/14/00	Inoue et al.			-
	FG	6,173,474	01/16/01	Conrad		 	
	FH	6,180,252	01/30/01	Farrell et al.		 	
-	FI	4,242,595	12/30/0	Lehovec		1	
	FJ	4,398,342	08/16/83	Pitt et al.			
	FK	4,424,589	01/03/84	Thomas et al.		<u> </u>	
	FL	4,876,208	10/24/89	Gustafson et al.		1	
	FM	4,482,422	11/84	McGinn et al.		1	
-	FN	4,667,088	05/19/87	Kramer		 	
	FO	4,772,929	09/20/88	Manchester et al.			
	FP	4,841,775	06/27/89	Ikeda et al.		1	
O.	FQ	4,845,044	07/04/89	Ariyoshi et al.		†	

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GA 4,868,376 09/19/89 Lessin et al.	6
GB 4,885,376 12/05/89 Verkade	
GC 4,888,202 12/89 Murakami et al.	
GD 4,891,091 12/90 Wanlass et al.	
GE 5,051,790 09/24/91 Hammer	
GF 5,055,445 10/08/91 Belt et al.	
GG 5,081,519 11/14/92 Nishimura et al.	
GH 5,143,854 09/01/92 Pirrung et al.	
GI 5,185,589 02/09/93 Krishnaswamy et al.	
GJ 5,191,625 03/02/93 Gustavsson	
GK 5,194,397 03/16/93 Cook et al.	
GL 5,208,182 05/04/93 Narayan et al.	
GM 5,216,729 06/01/93 Berger et al.	
GN 5,314,547 05/24/94 Heremans et al.	
GO 5,352,926 10/04/94 Andrews	
GP 5,356,509 10/18/94 Terranova et al.	
GQ 5,371,734 12/06/94 Fischer	
GR 5,372,992 12/94 Itozaki et al.	
GS 5,405,802 04/11/95 Yamagata et al.	
GT 5,442,561 08/15/95 Yoshizawa et al.	
GU 5,453,727 09/26/95 Shibasaki et al.	
GV 5,466,631 11/14/95 Ichikawa et al.	
GW 5,473,047 12/05/95 Shi	
GX 5,473,171 12/95 Summerfelt	
GY 5,479,033 12/26/95 Baca et al.	
GZ 5,486,406 01/23/96 Shi	
HA 5,491,461 02/13/96 Partin et al.	
HB 5,492,859 02/20/96 Sakaguchi et al.	
HC 5,494,711 02/27/96 Takeda et al.	
HD 5,504,035 04/02/96 Rostoker et al.	
HE 5,504,183 04/02/96 Shi	
HF 5,511,238 04/23/96 Bayraktaroglu	
HG 5,512,773 04/96 Wolf et al.	
HH 5,515,047 05/07/96 Yamakido et al.	
HI 5,515,810 05/14/96 Yamashita et al.	
HJ 5,519,235 05/96 Ramesh	
HK 5,549,977 08/96 Uin et al.	
HL 5,551,238 09/03/96 Prueitt	
HM 5,552,547 09/03/96 Shi	
HN 5,589,284 12/31/96 Summerfelt et al.	
HO 5,602,418 02/11/97 Imai et al.	
i HP 5,633,724 05/27/97 King et al.	

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Barbara F. BARENBURG, et al

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	IE ΔΡΡΟΣΟΡΡΙΔΙΕ
0	IΑ	5,650,646	07/22/97	Summerfelt			200c
1	ΙΒ	5,656,382	08/12/97	Nashimoto			52
	ic	5,659,180	08/19/97	Shen et al.			000
	ID	5,661,112	08/26/97	Hatta et al.			
	IE	5,679,965	11/95	Schetzina			
	IF	5,725,641	03/10/98	MacLeod			
	IG	5,745,631	04/28/98	Reinker			
	IH	5,776,621	07/07/98	Nashimoto			
	11	5,777,350	07/07/98	Nakamura et al.		:	
-	IJ	5,789,845	08/04/98	Wadaka et al.			
	iK	5,792,569	08/11/98	Sun et al.		1	
	IL.	5,792,679	08/11/98	Nakato		-	
	IM	5,796,648	08/18/98	Kawakubo et al.			
	IN	5,801,072	09/01/98	Barber			
	10	5,812,272	09/22/98	King et al.			·-
				Itozaki et al.			
	IP	5,814,583	09/98	<u> </u>			
	IQ	5,825,055	10/20/98	Summerfelt			
	IR	5,827,755	10/27/98	Yonchara et al.			
	IS	5,833,603	11/10/98	Kovacs et al.			
	IT	5,838,035	11/17/98	Ramesh			
	IU	5,844,260	12/01/98	Ohori			
	IV	5,846,846	12/08/98	Suh et al.			
	IW	5,863,326	01/26/99	Nause et al.			
	IX	5,872,493	02/16/99	Ella			
i	ΙΥ	5,879,956	03/99	Seon et al.			
	ΙZ	5,880,452	03/09/99	Plesko			
- !	JA	5,883,564	03/16/99	Partin			
	JВ	5,907,792	05/25/99	Droopad et al.			
1	JC	5,937,274	08/10/99	Kondow et al.		1 1	
	JD	5,948,161	09/07/99	Kizuki		† <u> </u>	· · · · · · · · · · · · · · · · · · ·
	JΕ	5,959,879	09/28/99	Koo			
	JF	5,966,323	10/99	Chen et al.		<u> </u>	
	JG	5,987,011	11/16/99	Toh		 	
	JН	6,022,140	02/08/00	Fraden et al.			
	JI	6,022,410	02/08/00	Yu et al.		 	
	אר	6,023,082	02/08/00	McKee et al.		+ +	
	JK	6,028,853	02/22/00	Haartsen			
	JL.	6,049,702	04/11/00	Tham et al.		 	
	NW.	6,078,717	06/20/00	Nashimoto et al		1	
	↓	6,088,216	07/00	Laibowitz et al.			
	hν						
	ho	6,090,659	07/00	Laibowitz et al.		 	
-	JP	6,107,721	08/22/00	Lakin			
(dis)	μQ	6,153,010	11/28/00	Kiyoku et al			

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Barbara F. BARENBURG, et al. GROUP

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EXAMINER	T	DOCUMENT	DATE	U.S. PATENT DOCUMENTS NAME	CLASS	SUB	FILING Q ATE
INITIAL		NUMBER		<u> </u>	CLASS	CLASS	IF APPROPRIATE
000	KA	6,153,454	11/28/00	Krivokapic			308,
	KB	6,191,011	02/01	Gilboa et al			
	KC	6,204,737	03/20/01	Ella			
	KD	6,224,669	05/01/01	Yi et al.			
	KE	6,225,051	05/01/01	Sugiyama et al.			
	KF	6,241,821	06/05/01	Yu et al.			
	KG	6,265,749	07/24/01	Gardner et al.			-
	KH	6,313,486	11/01	Kencke et al.			
	ΚI	6,316,832	11/13/01	Tsuzuki et al.			,
	KJ	2002/0008234	01/02	Emrick			
	KK	3,670,213	06/13/72	Nakawaga et al.			
	KL	4,756,007	07/05/88	Qureshi et al.			
	KM	4,773,063	09/20/88	Hunsperger et al.			
	KN	5,394,489	02/28/95	Koch			
	ко	5,406,202	04/11/95	Mehrgardt et al.			
	KP	5,528,067	06/18/96	Farb et al.			
	KQ	5,572,052	11/05/96	Kashihara et al.			
	KR	5,767,543	06/16/98	Ooms et al.			
	KS	6,175,497	01/16/01	Tseng et al.			
	KT	6,197,503	03/06/01	Vo-Dinh et al.	1		
	KU	6,248,459	06/19/01	Wang et al.			
	ΚV	6,252,261	06/26/01	Usui et al.			
	KW	6,255,198	07/03/01	Linthicum et al.			-
	кх	6,268,269	07/31/01	Lee et al.			
	KY	6,291,319	09/18/01	Yu et al.			
	ΚZ	6,316,785	11/13/01	Nunoue et al.			
	LA	6,343,171	01/29/02	Yoshimura et al.			
	LB	4,965,649	10/23/90	Zanio et al.			-
	LC	6,253,649	05/01	Kawahara et al.			
	LD	6,211,096	04/01	Allman et al.			
	LE	6,239,449	05/29/01	Fafard et al.			
	LF	2001/0013313	08/16/01	Droopad et al.			
	LG	6,184,044	02/06/01	Sone et al.			
	LH	6,011,646	01/04/00	Mirkarimi et al.			
	LI	5,227,196	07/13/93	Itoh			
:	LJ	6,150,239	11/21/00	Goesele et al.			
	LK	5,441,577	08/15/95	Sasaki et al.			
	LL	4,459,325	07/10/84	Nozawa et al.			
	LM	4,392,297	07/12/83	Little			
	LN	4,289,920	09/15/81	Hovel			
	LO	5,281,834	01/25/94	Cambou et al.			
	LP	4,901,133	02/13/90	Curran et al.			
Or	LQ	5,514,904	05/07/96	Onga et al.			

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		941;	27 20 3	S. PATENT DOCUMENTS			
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00	MA	5,553,089	703/03/9 6	Seki et al.			RECEIVE ARCHIO
1	МВ	5,528,057	06/18/96	Yanagase et al.			<u>E</u> 71
	МС	6,229,159	05/08/01	Suzuki			智田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田田
	MD	4,748,485	05/31/88	Vasudev			CORT
	ME	4,984,043	01/08/91	Vinal			9 1 里
	MF	5,754,319	05/19/98	Van De Voorde et al.			DENTER
	MG	6,108,125	08/22/00	Yano			J3 (ER
	мн	5,073,981	12/17/91	Giles et al.			, 28
	MI	5,140,651	08/18/92	Soref et al.			2800
	MJ	5,610,744	03/11/97	Ho et al.			
	MK	6,362,017	03/26/02	Manabe et al.			
	ML	6,242,686	06/05/01	Kishimoto et al.			
	ММ	5,689,123	11/18/97	Major et al.			
	MN	5,670,800	09/23/97	Nakao et al.			
	МО	5,067,809	11/26/91	Tsubota			
	MP	5,596,205	01/21/97	Reedy et al.			
	MQ	6,175,555	01/16/01	Hoole			
	MR	5 ,357,122	10/18/94	Okubora et al.			
	MS	4,084,130	04/11/78	Holton	1		
	МТ	6,093,302	07/25/00	Montgomery			
	ΜU	6,372,813	04/16/02	Johnson et al.			
	MV	5,608,046	03/04/97	Cook et al.			
	MW	5,955,591	09/21/99	Imbach et al.			
	MX	6,022,963	02/08/00	McGall et al.			
	MY	6,083,697	07/04/00	Beecher et al.			
	MZ	5,063,081	11/05/91	Cozzette et al.			
	NA	5,479,317	12/26/95	Ramesh			
	NB	5,306,649	04/26/94	Hebert			
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